

ON Semiconductor®

FDS6690A

Single N-Channel, Logic-Level, PowerTrench® MOSFET

General Description

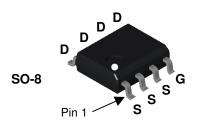
This N-Channel Logic Level MOSFET is produced using ON Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

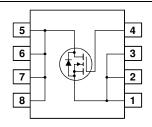
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.



Features

- 11 A, 30 V. $R_{DS(ON)} = 12.5 \ m\Omega \ @V_{GS} = 10 \ V$ $R_{DS(ON)} = 17.0 \ m\Omega \ @V_{GS} = 4.5 \ V$
- · Fast switching speed
- · Low gate charge
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1a)	11	Α
	- Pulsed		50	
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.0	
E _{AS}	Single Pulse Avalanche Energy	(Note 3)	96	mJ
T _J , T _{STG}	Operating and Storage Junction Temperat	ture Range	-55 to +150	°C

Thermal Characteristics

R _{θJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
R _{θJA}	Thermal Resistance, Junction-to-Ambient	(Note 1b)	125	
R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	25	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS6690A	FDS6690A	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		1			1
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_D = 250 \mu\text{A}$	30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current $V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$				1	μΑ
		$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55^{\circ}\text{C}$			10	μΑ
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Chara	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1	1.9	3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		- 5		mV/°C
$R_{DS(on)}$	Static Drain–Source On–Resistance	$\begin{split} V_{GS} &= 10 \ V, & I_D &= 11 \ A \\ V_{GS} &= 4.5 \ V, & I_D &= 10 \ A \\ V_{GS} &= 10 \ V, I_D &= 11 \ A, T_J &= 125 ^{\circ}C \end{split}$		9.8 12.0 13.7	12.5 17.0 22.0	mΩ
I _{D(on)}	On-State Drain Current	V _{GS} = 10 V, V _{DS} = 5 V	50			Α
g _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 11 \text{ A}$		48		S
Dynamic	Characteristics					•
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$ f = 1.0 MHz		1205		pF
Coss	Output Capacitance			290		pF
C _{rss}	Reverse Transfer Capacitance			115		pF
R _G	Gate Resistance	V _{GS} = 15 mV, f = 1.0 MHz		2.4		Ω
Switchin	g Characteristics (Note 2)					•
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$		9	19	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		5	10	ns
t _{d(off)}	Turn-Off Delay Time			28	44	ns
t _f	Turn-Off Fall Time	7		9	19	ns
Q _g	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 11 \text{ A},$		12	16	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 5 V		3.4		nC
Q _{gd}	Gate-Drain Charge			4.0		nC
Drain-Sc	ource Diode Characteristics	and Maximum Ratings		,		
Is	Maximum Continuous Drain-Source	•			2.1	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \qquad I_S = 2.1 \text{ A (Note 2)}$		0.74	1.2	V
t _{rr}	Diode Reverse Recovery Time	1 11 0 0 /d 100 0 /:-		24		nS
Q _{rr}	Diode Reverse Recovery Charge	$I_F = 11 \text{ A}, d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		27		nC

Notes:

^{1.} R_{aJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $\rm\,R_{\theta JC}$ is guaranteed by design while $\rm\,R_{\theta CA}$ is determined by the user's board design.



a) 50 °C/W when mounted on a 1in² pad of 2 oz copper



b) 125°C/W when mounted on a minimum pad.

Scale 1:1 on letter size paper

2 Test: Pulse Width < 300 μ s, Duty Cycle < 2.0% 3. Starting TJ = 25°C, L = 3mH, μ S = 8A, ν DD = 30V, ν S = 10V

Typical Characteristics

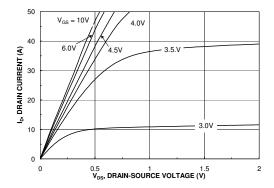


Figure 1. On-Region Characteristics.

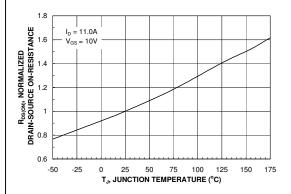


Figure 3. On-Resistance Variation with Temperature.

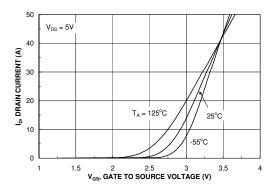


Figure 5. Transfer Characteristics.

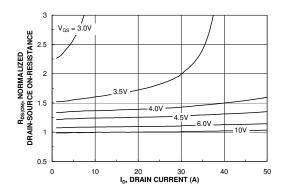


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

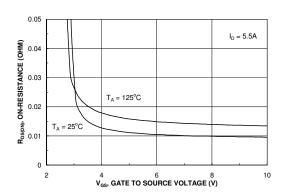


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

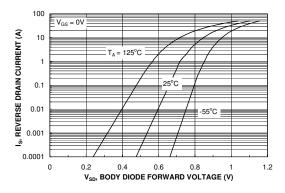
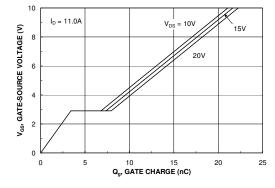


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



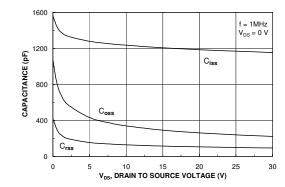
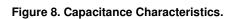
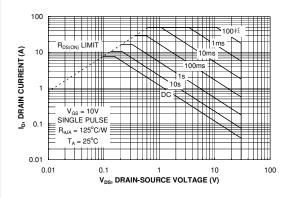


Figure 7. Gate Charge Characteristics.





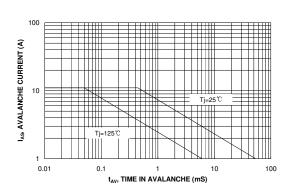
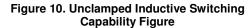


Figure 9. Maximum Safe Operating Area.



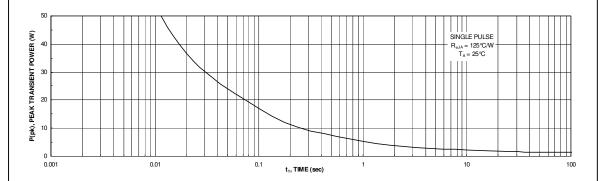


Figure 11. Single Pulse Maximum Power Dissipation.

Typical Characteristic

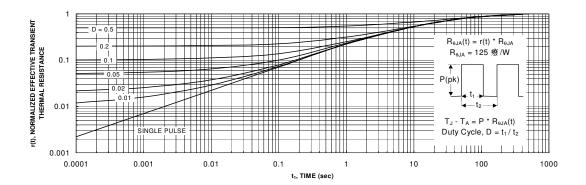


Figure 12. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hol

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800-282-9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Phone: 421 33 790 2910

Japan Customer Focus Center
Phone: 81–3–5817–1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative